

Notice of References Cited	Application/Control No. 10/642,318	Applicant(s)/Patent Under Reexamination WAN ET AL.	
	Examiner David García Cervetti	Art Unit 2136	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,327,522 A	07-1994	Furuta et al.	706/43
*	B	US-6,201,870 B1	03-2001	Medard et al.	380/46
*	C	US-2002/0006197 A1	01-2002	Carroll et al.	380/44
*	D	US-2002/0097703 A1	07-2002	Nieczyporowicz et al.	370/342
*	E	US-6,480,072 B1	11-2002	Walsh et al.	331/78
*	F	US-2003/0059045 A1	03-2003	Ruehle, Michael D.	380/46
*	G	US-2003/0072059 A1	04-2003	Thomas et al.	359/167
*	H	US-2004/0049525 A1	03-2004	Hars, Laszlo	708/250
*	I	US-2004/0205095 A1	10-2004	Gressel et al.	708/253
*	J	US-2005/0066168 A1	03-2005	Walmsley, Simon Robert	713/169
*	K	US-6,879,689 B2	04-2005	Carroll et al.	380/44
*	L	US-6,993,542 B1	01-2006	Meiyappan, Subramanian	708/250
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.